

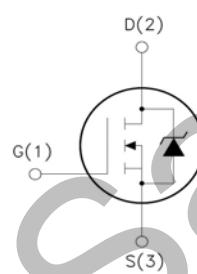
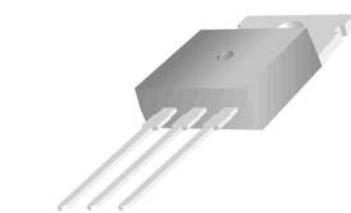
SM30N10

100V N-Channel MOSFET

Features:

- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge : $Q_g = 31\text{nC}$ (Typ.).
- $\text{BV}_DSS = 100\text{V}$, $I_D = 30\text{A}$
- $R_{DS(on)} : 0.07\Omega$ (Max) @ $V_G = 10\text{V}$
- 100% Avalanche Tested

TO-220



1.Gate (G)
2.Drain (D)
3.Source (S)

Absolute Maximum Ratings* ($T_c = 25^\circ\text{C}$ Unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	30	A
Drain Current-Continuous($T_c = 100^\circ\text{C}$)	$I_D (100^\circ\text{C})$	12	A
Pulsed Drain Current	I_{DM}	60	A
Maximum Power Dissipation	P_D	55	W
Single pulse avalanche energy (Note 5)	E_{AS}	250	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^\circ\text{C}$

Thermal Characteristics

Thermal Resistance, Junction-to-Case (Note 2)	$R_{\theta JC}$	2.27	$^\circ\text{C}/\text{W}$
---	-----------------	------	---------------------------

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	100	110	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$\text{V}_{\text{DS}}=100\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1.2	1.8	2.5	V
Drain-Source On-State Resistance	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=5\text{A}$	-	56	70	$\text{m}\Omega$
Forward Transconductance	g_{FS}	$\text{V}_{\text{DS}}=50\text{V}, \text{I}_D=9\text{A}$	12	-	-	S
Dynamic Characteristics (Note 4)						
Input Capacitance	C_{iss}	$\text{V}_{\text{DS}}=25\text{V}, \text{V}_{\text{GS}}=0\text{V},$ $F=1.0\text{MHz}$	-	1350	-	PF
Output Capacitance	C_{oss}		-	240	-	PF
Reverse Transfer Capacitance	C_{rss}		-	180	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	$t_{\text{d(on)}}$	$\text{V}_{\text{DD}}=30\text{V}, \text{I}_D=2\text{A}, \text{R}_L=15\Omega$ $\text{V}_{\text{GS}}=10\text{V}, \text{R}_G=2.5\Omega$	-	13.8	-	nS
Turn-on Rise Time	t_r		-	9.3	-	nS
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	43.8	-	nS
Turn-Off Fall Time	t_f		-	11.4	-	nS
Total Gate Charge	Q_g	$\text{V}_{\text{DS}}=30\text{V}, \text{I}_D=3\text{A},$ $\text{V}_{\text{GS}}=10\text{V}$	-	31	-	nC
Gate-Source Charge	Q_{gs}		-	6.4	-	nC
Gate-Drain Charge	Q_{gd}		-	9.4	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V_{SD}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_S=9\text{A}$	-	-	1.2	V
Diode Forward Current (Note 2)	I_S		-	-	30	A
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition : $\text{T}_j=25^\circ\text{C}, \text{VDD}=50\text{V}, \text{VG}=10\text{V}, \text{L}=0.5\text{mH}, \text{R}_G=25\Omega$

Typical Electrical and Thermal Characteristics (Curves)

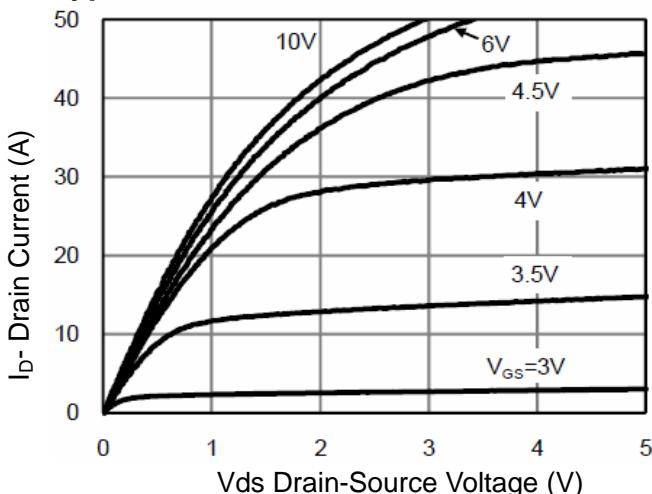


Figure 1 Output Characteristics

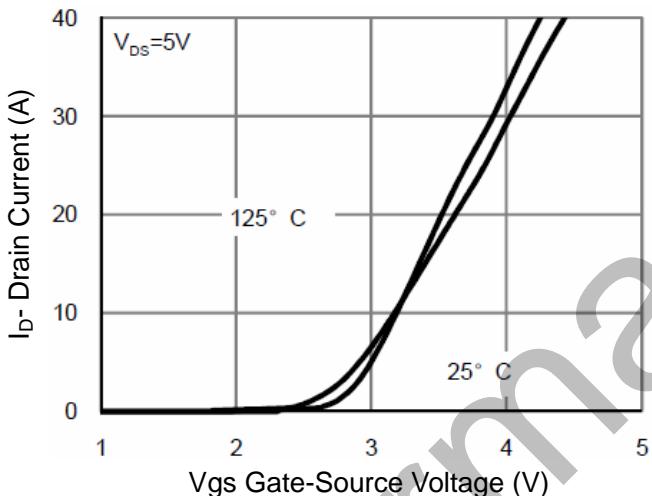


Figure 2 Transfer Characteristics

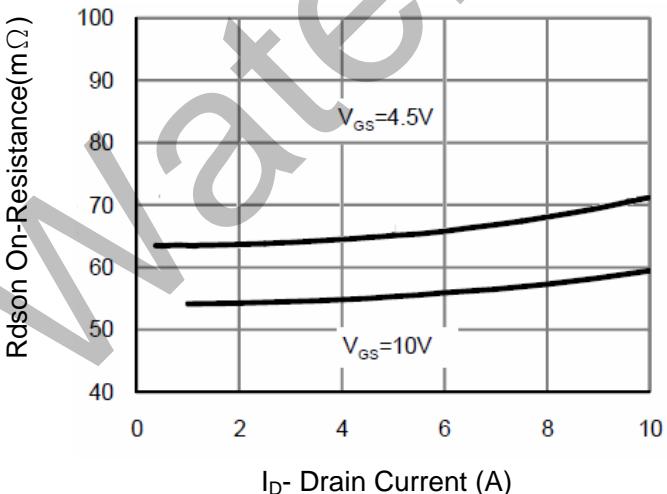


Figure 3 Rdson- Drain Current

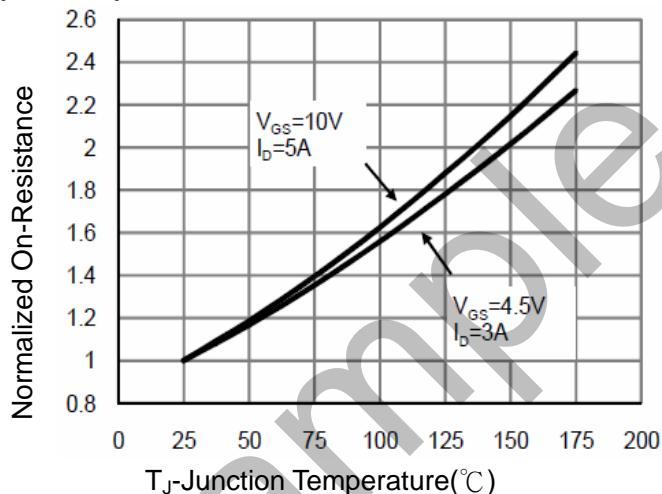


Figure 4 Rdson-JunctionTemperature

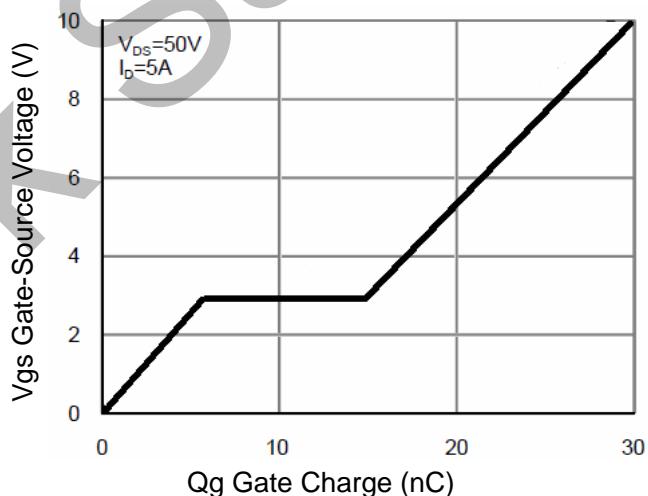


Figure 5 Gate Charge

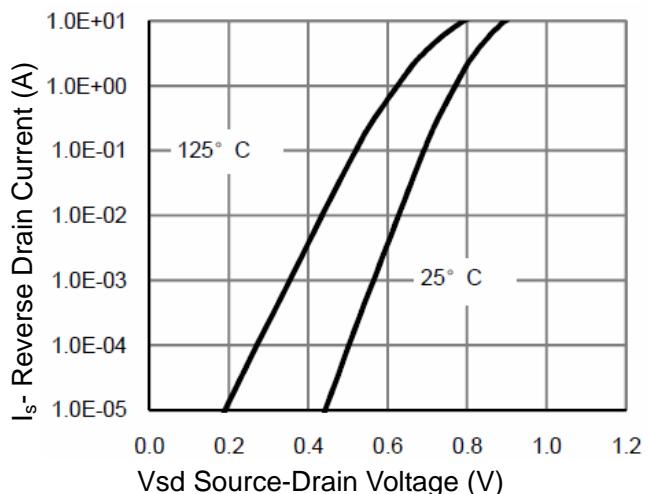


Figure 6 Source- Drain Diode Forward

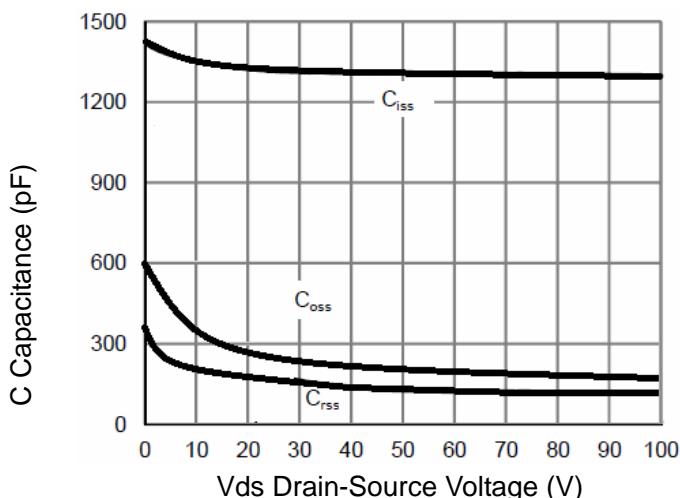


Figure 7 Capacitance vs Vds

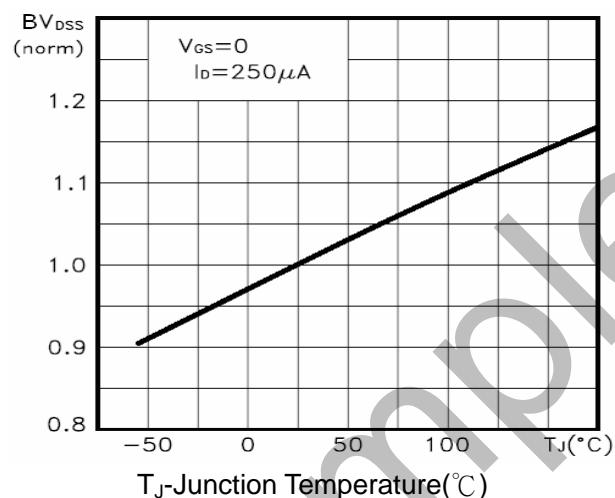


Figure 9 BV_{DSS} vs Junction Temperature

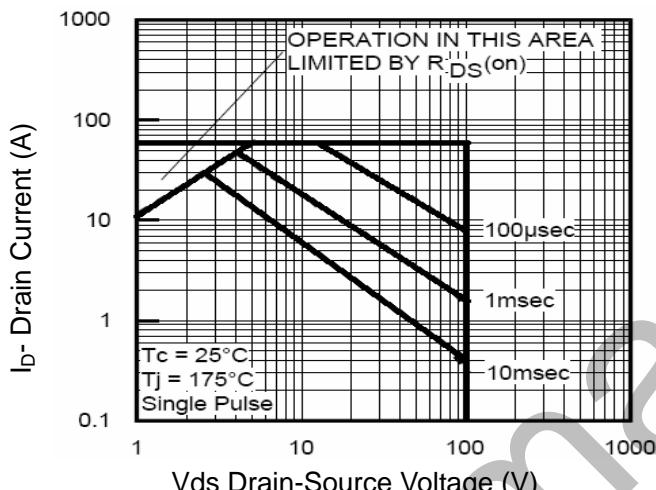


Figure 8 Safe Operation Area

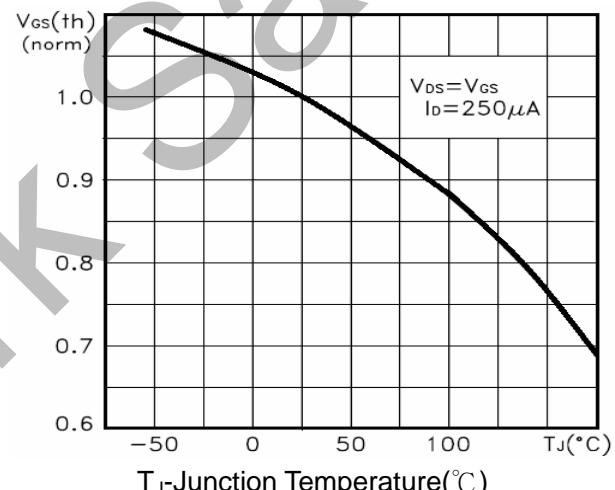


Figure 10 $V_{GS(th)}$ vs Junction Temperature

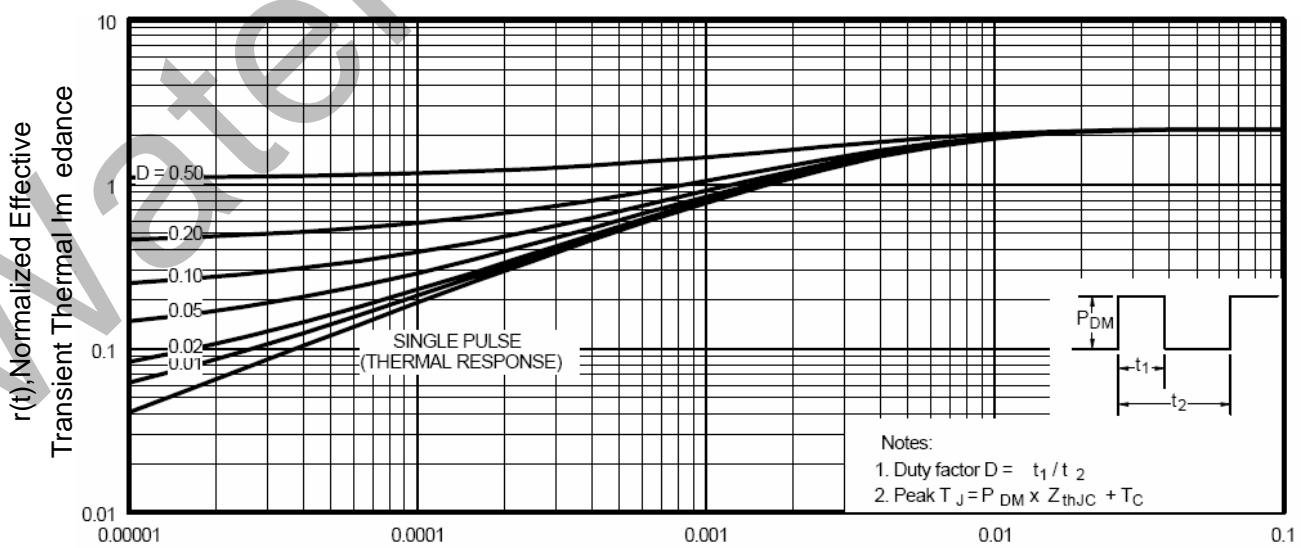
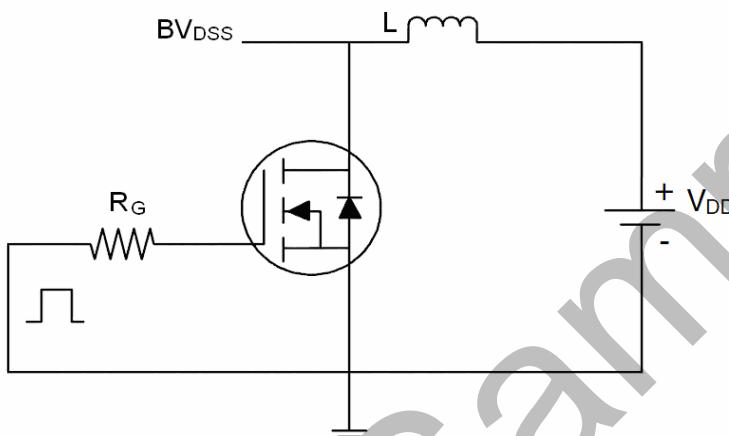


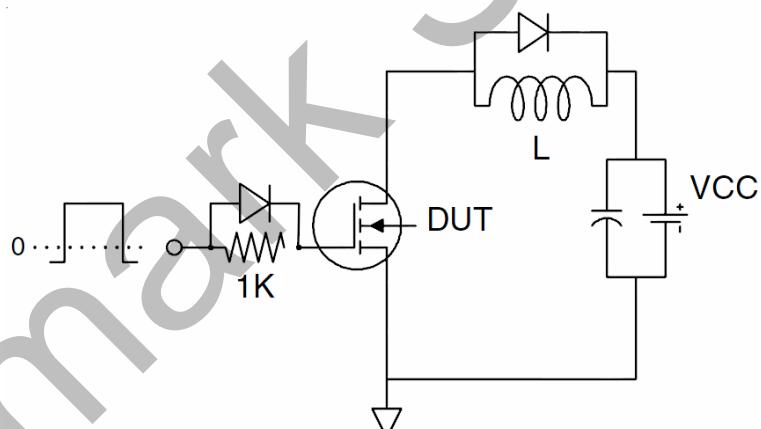
Figure 11 Normalized Maximum Transient Thermal Impedance

Test Circuit

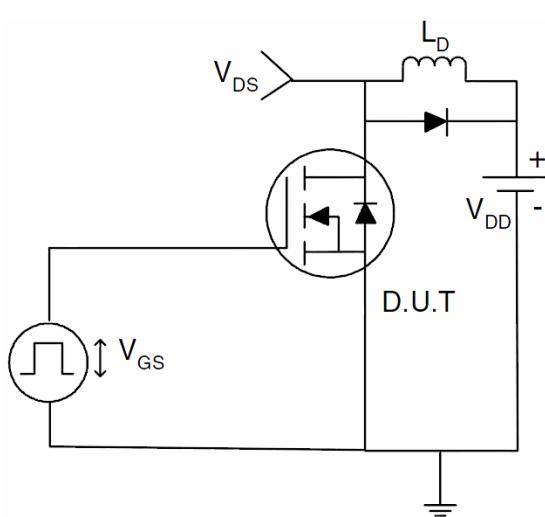
1) E_{AS} test Circuit



2) Gate charge test Circuit



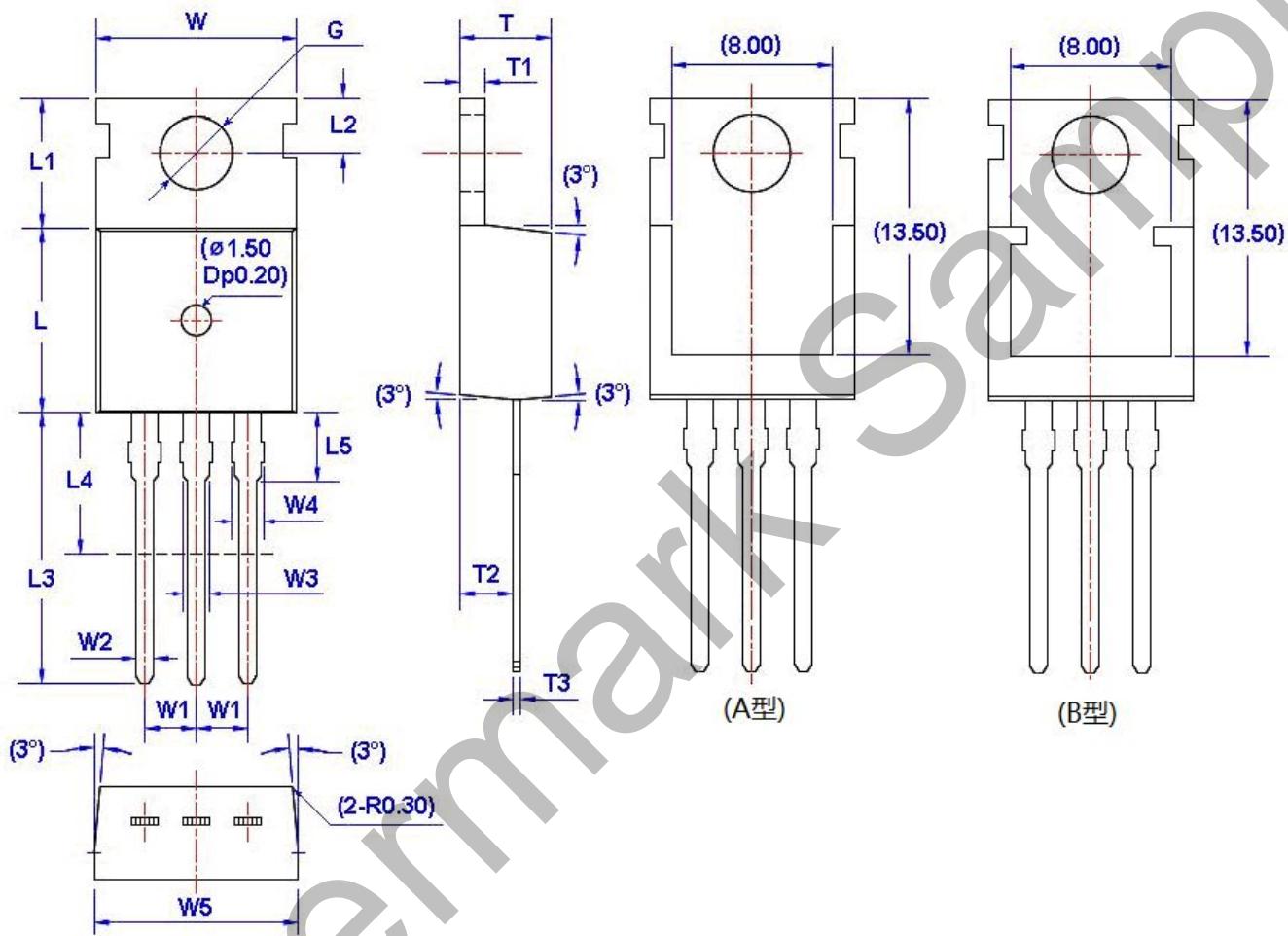
3) Switch Time Test Circuit



Package Dimension

TO-220

Unit:mm



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.66	10.28	W5	9.80	10.20	L4**	6.20	6.60	T3	0.45	0.60
W1	2.54 (TYP)		L	9.00	9.40	L5	2.79	3.30	G(Φ)	3.50	3.70
W2	0.70	0.95	L1	6.40	6.80	T	4.30	4.70			
W3	1.17	1.37	L2	2.70	2.90	T1	1.15	1.40			
W4*	1.32	1.72	L3	12.70	14.27	T2	2.20	2.60			